Application/Control No.	Applicant(s)/Patent under Reexamination	
10/822,243	BILENSKI ET AL.	
Examiner	Art Unit	
(Jackie) Tan-Uyen T. Ho	3731	

	SEAR	CHED	
Class	Subclass	Date	Examiner
606	167-170	8/10/2005	-08
30	49		
	351		
	357		
\downarrow	152		
30	294	8/10/2005	100
•			
·			

INTERFERENCE SEARCHED		
Subclass	Date	Examiner
167	9/22/0	M
	1	
	Subclass	Subclass Date

(INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
		-
•		
•		
·		